



Surge Current Withstanding Resistor Replacement for ER Carbon Composition

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Acronyms

- ER – Established Reliability
- NEPP Program – NASA Electronic Parts and Packaging Program
- QPL – Qualified Products List
- SMD – Surface Mount Devices



Background

- Established Reliability Carbon Composition Resistors
 - Popular in power supply applications
 - MIL-R-39008
 - Last QPL supplier exited market in 1996/Specification cancelled in 1998
- “Surge” capability was not a documented parameter in military specifications
 - Bulk carbon material effective at absorbing energy/heat during pulse without degradation
- Pockets of existing QPL inventory are becoming scarce; now more than twenty-five years old



Work Performed

- Identify different manufacturer/technology devices advertised as “surge” resistant or replacement for carbon composition resistors. Select a cross section of manufacturers, technologies, and packages.
 - While chip components were selected, only leaded parts were able to be reliably testing in the assembled test fixture.
- Obtain samples of various parts and subject them to various voltage/energy pulses to assess susceptibility to damage.

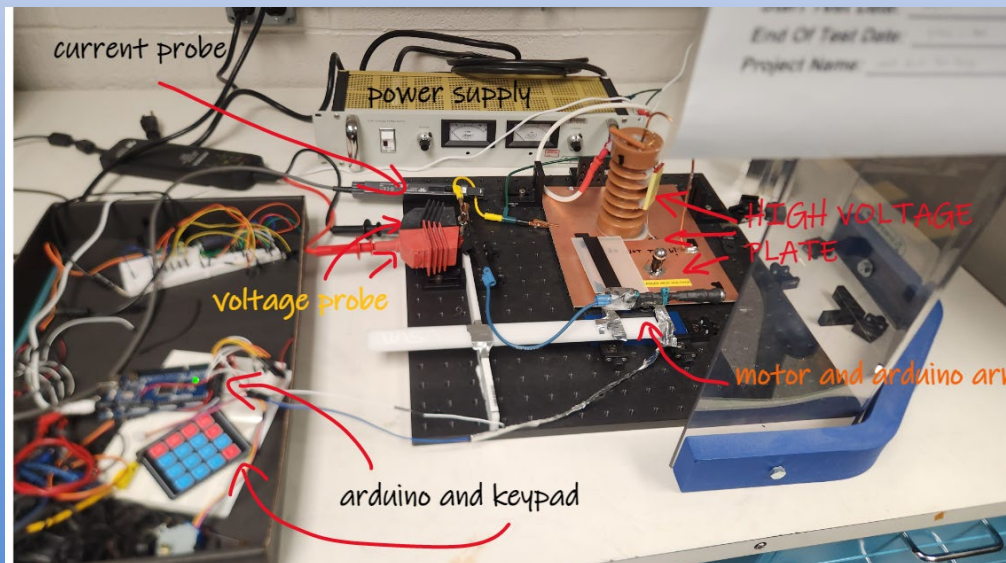


Manufacturer/Technology

Manufacturer	Value (ohm)	Tolerance	Rated Voltage (Vdc)	Rated Surge (Vdc)	Package Type
A	100	+/- 5%	300	NR	Axial
A	1000	+/- 5%	300	NR	Axial
A	10000	+/- 5%	300	NR	Axial
A	100000	+/- 10%	300	NR	Axial
B	560	+/- 10%	350	700	Axial
B	1200	+/- 10%	350	700	Axial
B	100000	+/- 10%	350	700	Axial
C	100	+/- 10%	350	700	Axial
C	2200	+/- 10%	350	700	Axial
C	10000	+/- 10%	350	700	Axial
D	220	+/- 5%	500	NR	Axial
D	1000	+/- 5%	500	NR	Axial
D	8200	+/- 5%	500	NR	Axial
D	47000	+/- 5%	500	NR	Axial
E	100000	+/- 5%	10000	10000	Axial
F	20000	+/- 5%	7000	7000	Axial
F	100000	+/- 5%	7000	7000	Axial
G	2200	+/- 10%	500	14000	Axial
G	100000	+/- 10%	500	14000	Axial
H	100	+/- 10%	300	14000	Axial
H	1000	+/- 10%	300	14000	Axial
H	100000	+/- 10%	300	7000	Axial
H	220000	+/- 10%	300	7000	Axial

Test Fixture

- Initial test fixture developed in collaboration with Steve Battel, Battel Engineering Inc.
- Jacob Hobbaugh (co-op, Drexel Univ) developed Arduino control system to control pulse contact mechanism.





Testing Performed

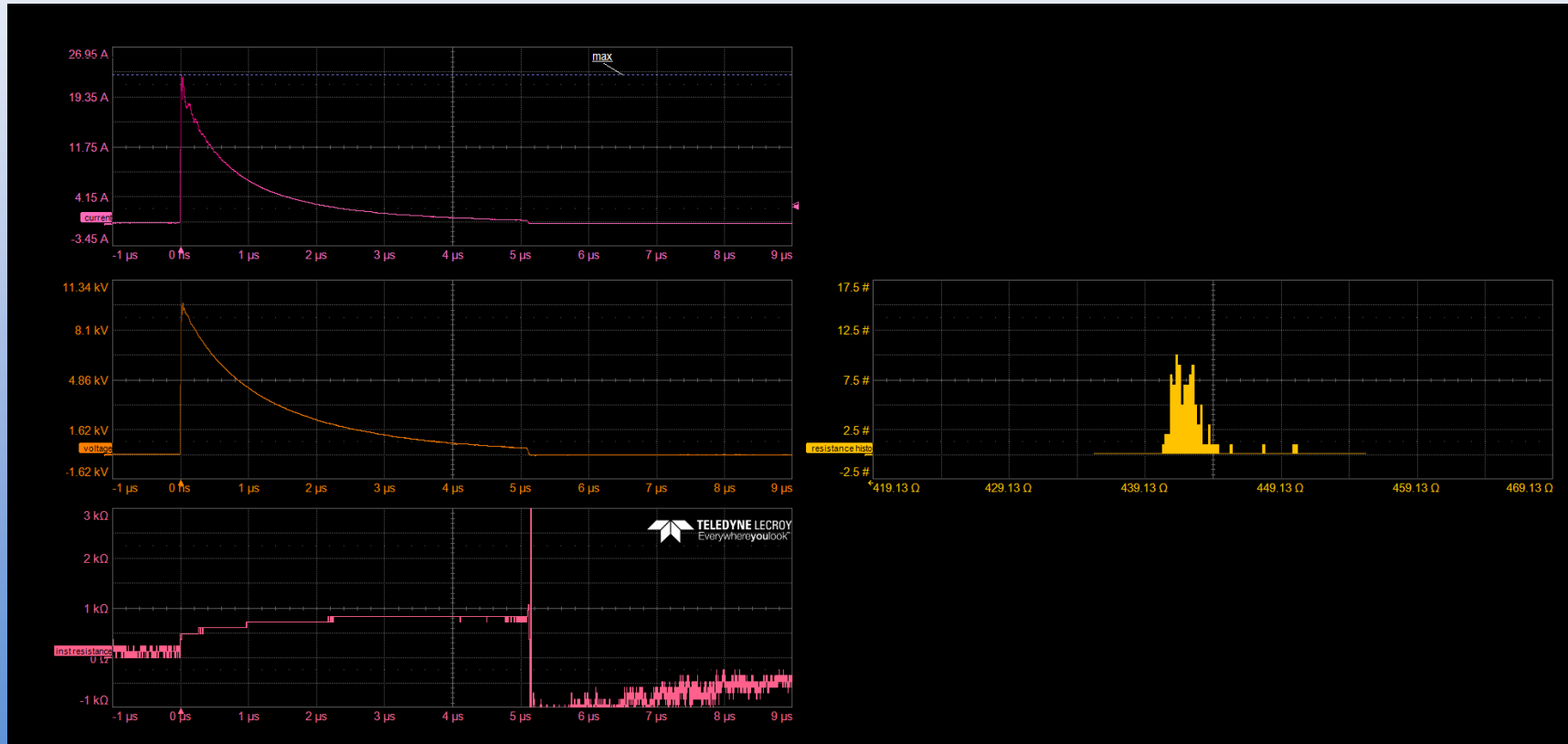
- The following testing was performed on all samples (except controls)
 - 2,000V, 10 pulses; 4,000V, 50 pulses; 10,000V, 20 pulses; 10,000V, 100 pulses
 - Testing performed by Jacob Hobaugh, Marialena Troia, Kellan McCarthy
- Note that the joule energy per pulse was calculated using

$$Energy = \frac{1}{2} C \times V^2$$

- 2,000V, $Energy \approx \frac{1}{2} (.002 \mu F) \times (2000 V)^2 = 4 mJ / pulse$
- 4,000V, $Energy \approx 16 mJ / pulse$
- 10,000V, $Energy \approx 100 mJ / pulse$
- Total Energy pulsed into each resistor = 12.840J

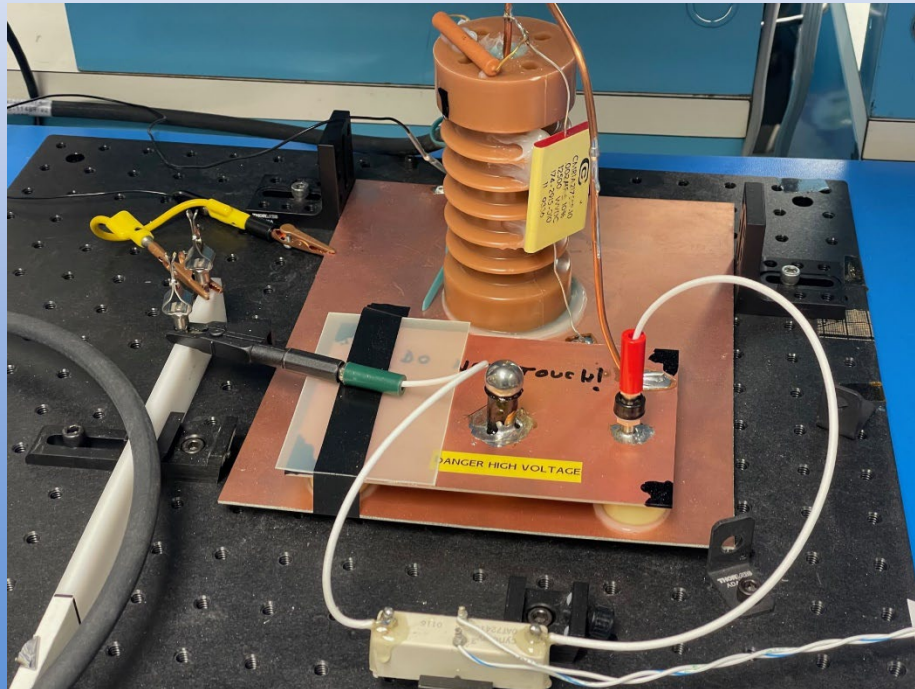
Pulse Shape

- Manufacturer H, 1k Ω , SN3

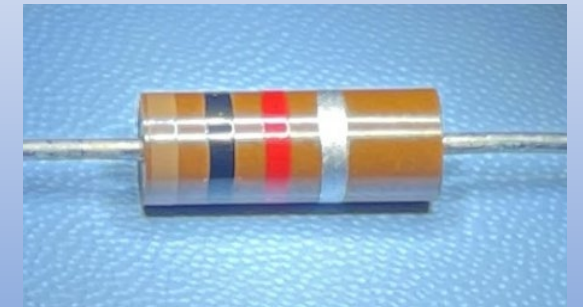
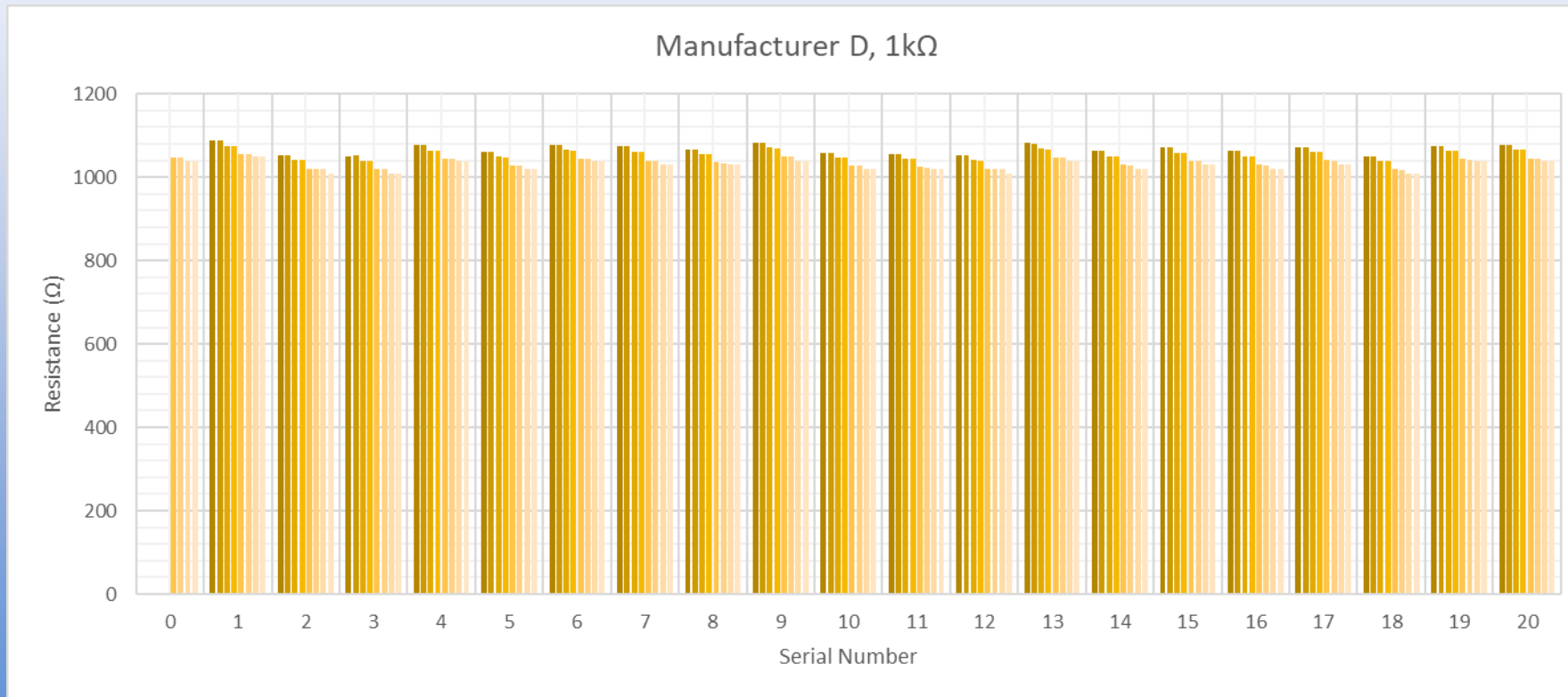


Test Fixture - Modified

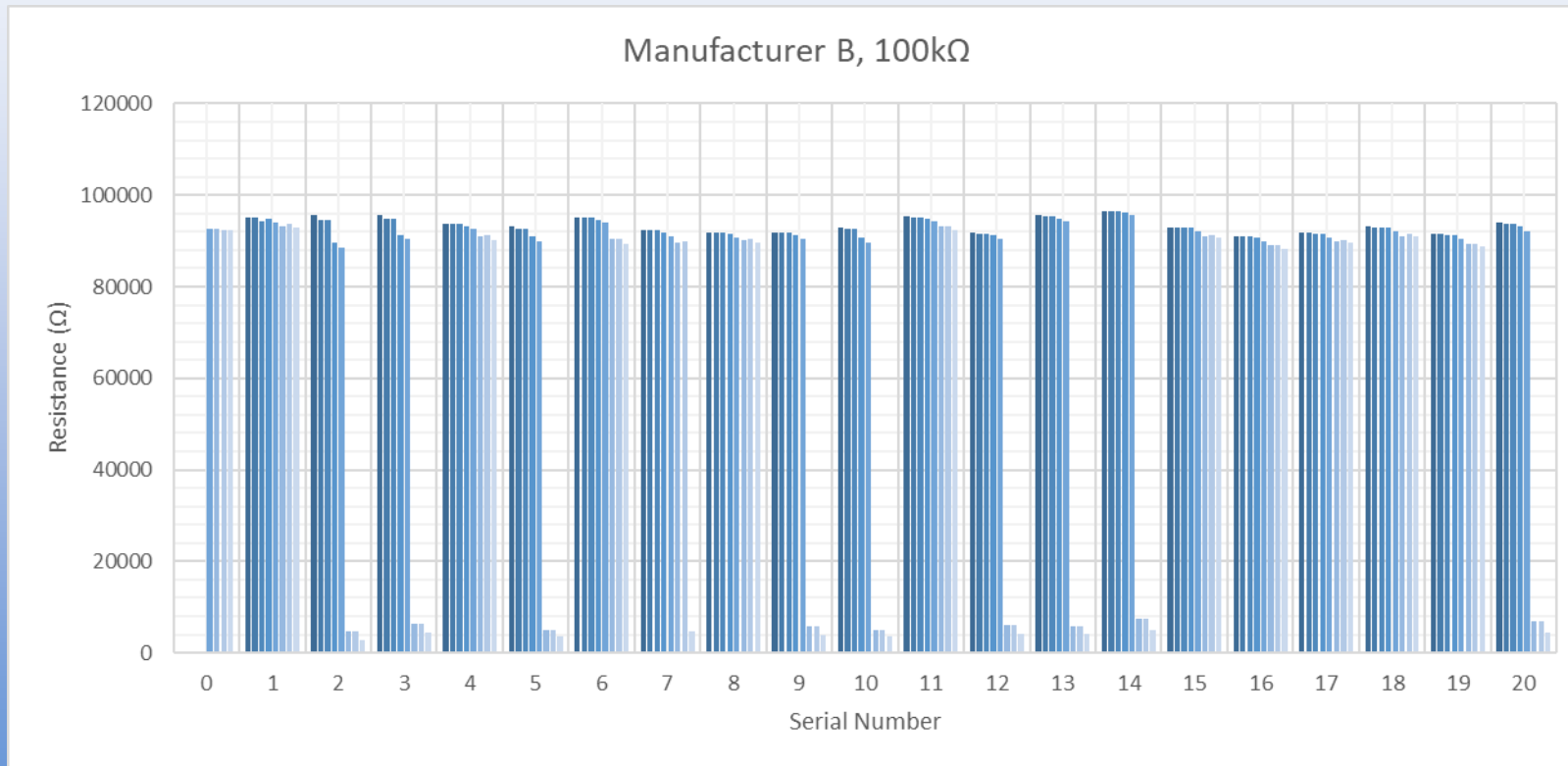
- After several thousand pulses, the ball bearing “pulser” began to weld on contact and testing had to be halted.
 - Ball bearing pulse mechanism was replaced with relay



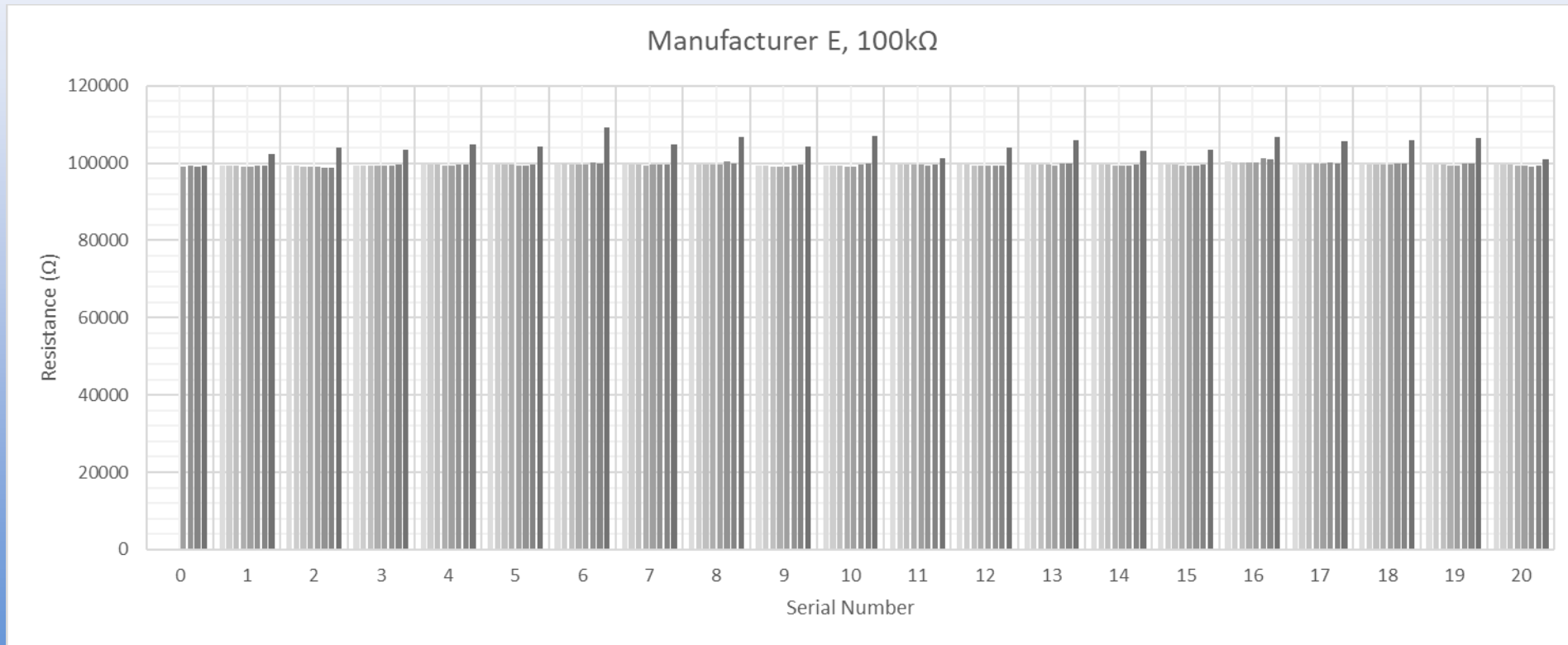
Sample Data - Typical Resistance Degradation Over Pulse Testing



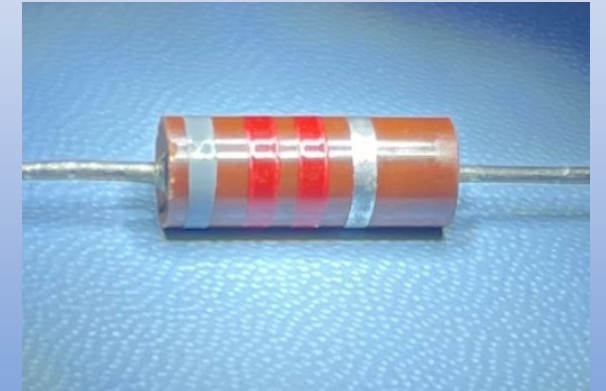
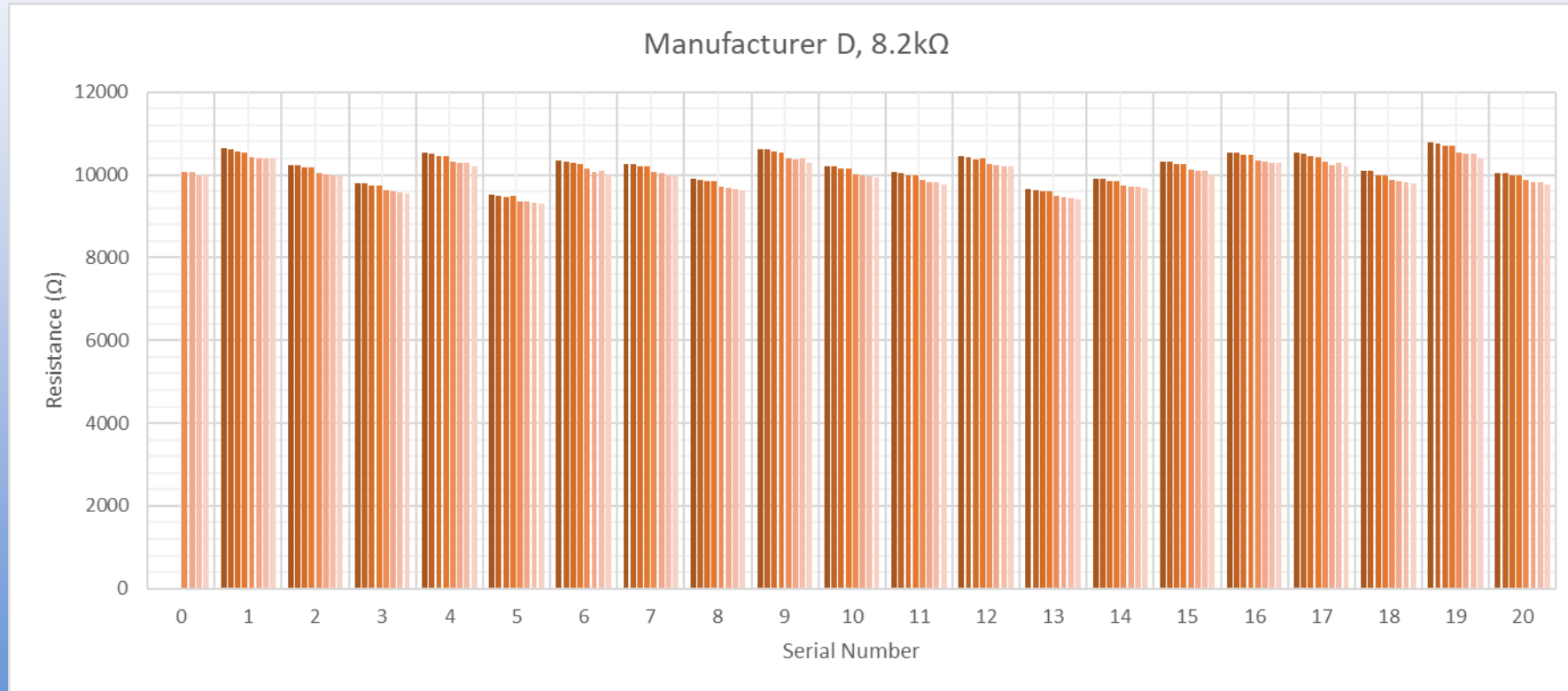
Sample Data – Catastrophic Resistance Degradation Across Pulse Testing



Sample Data – Outlier Resistance Increase

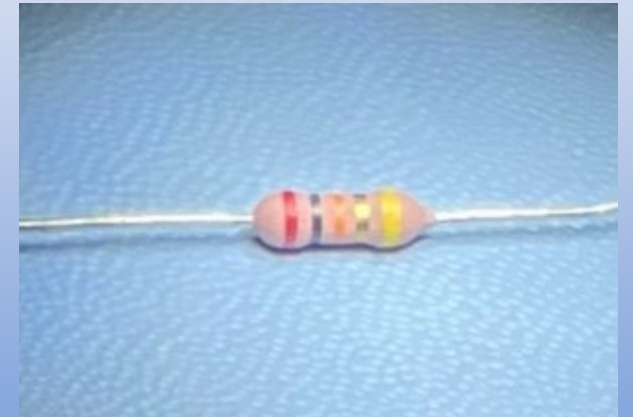
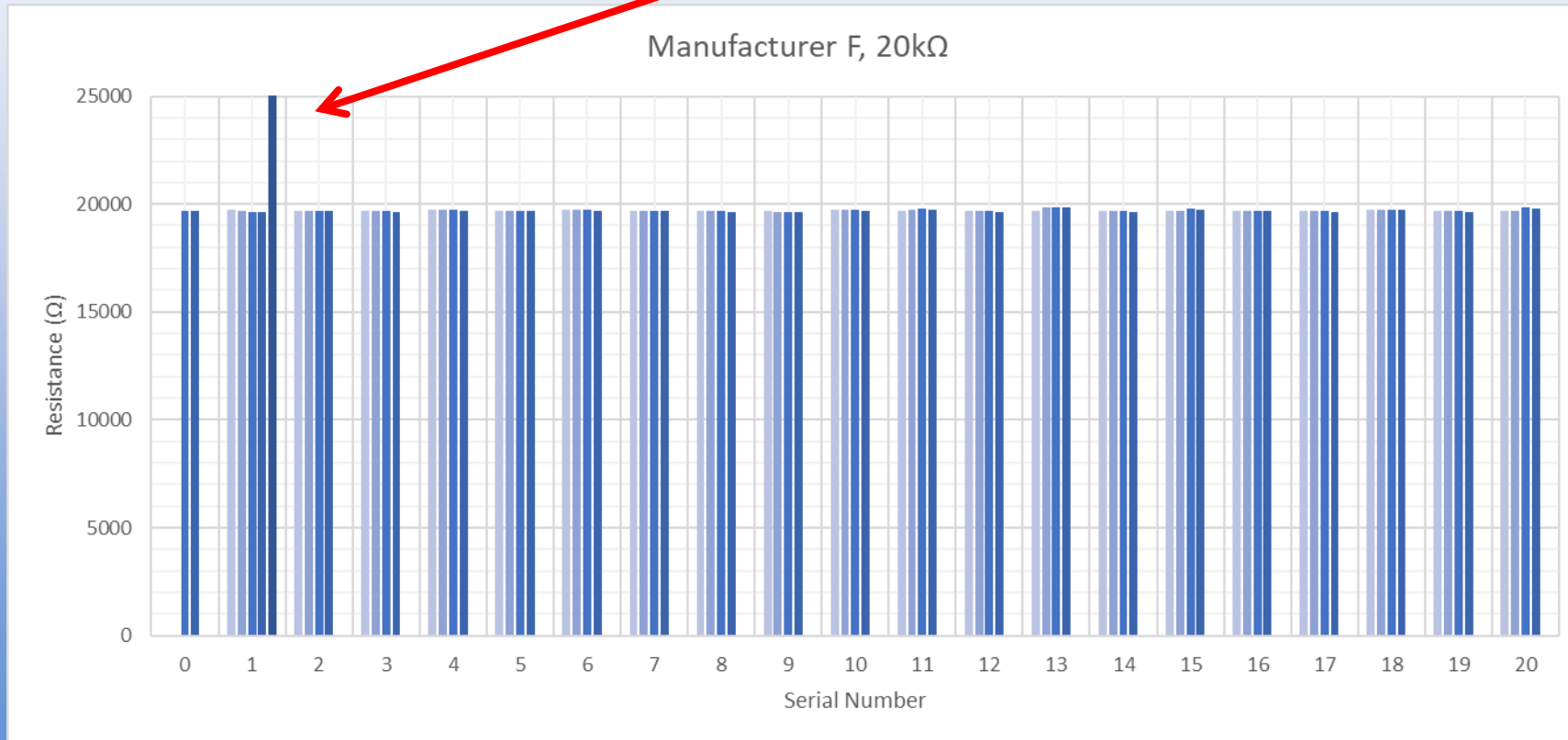


Sample Data - Color Code Not Matching Measurement

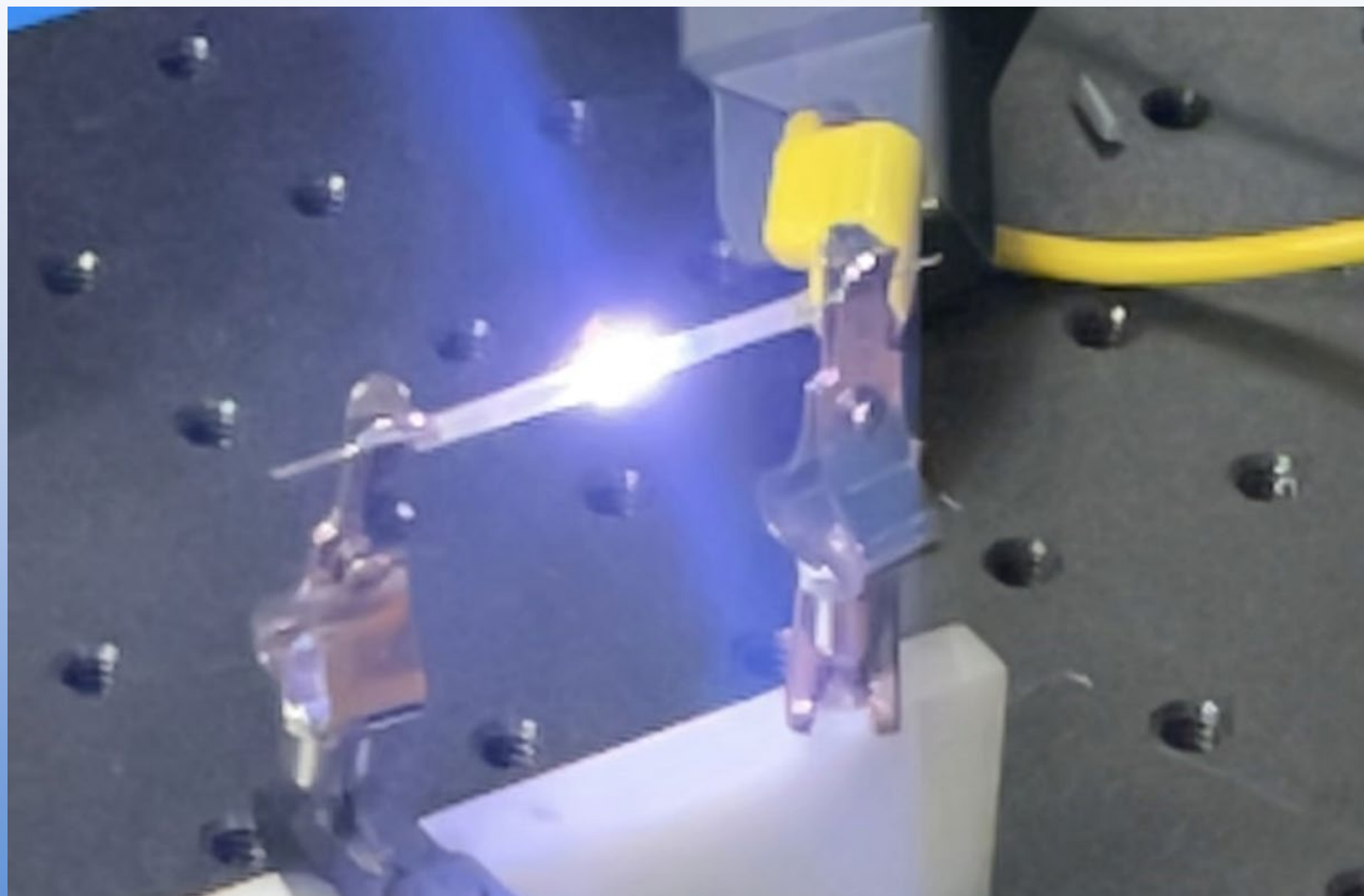


Sample Data – Open Circuit

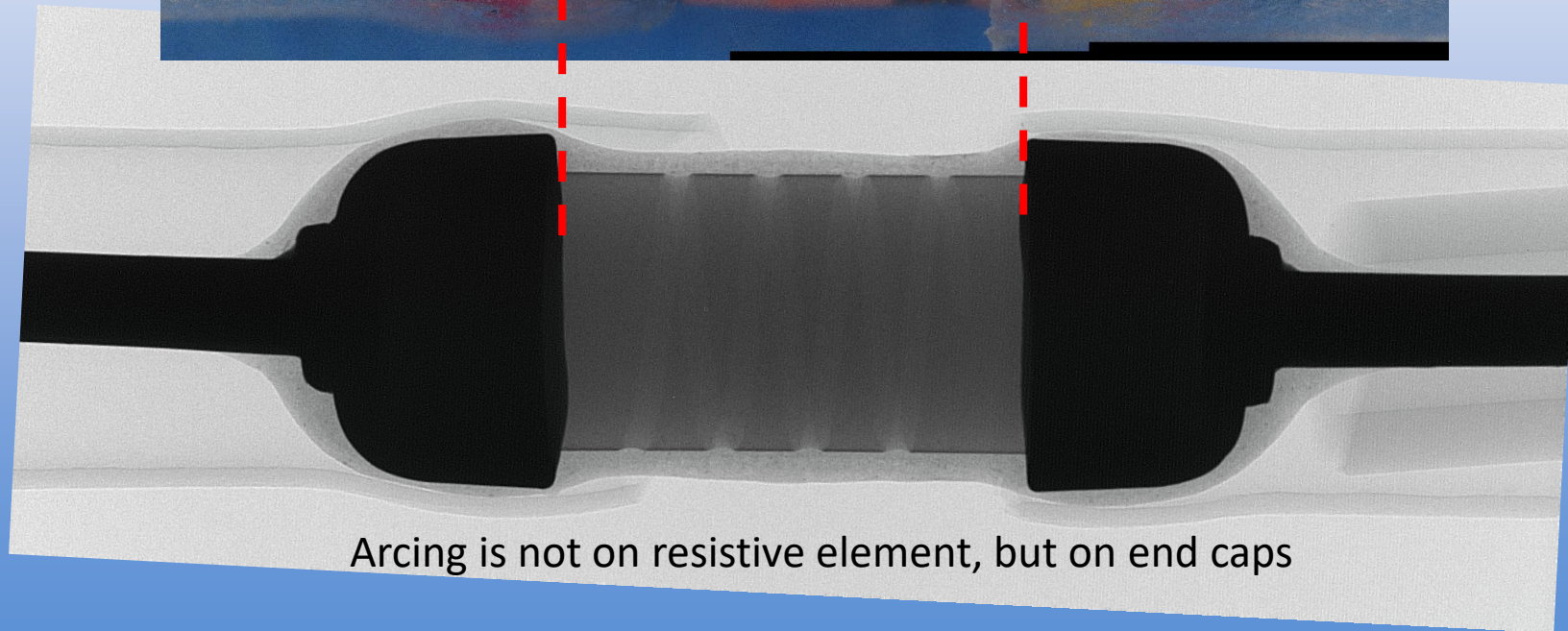
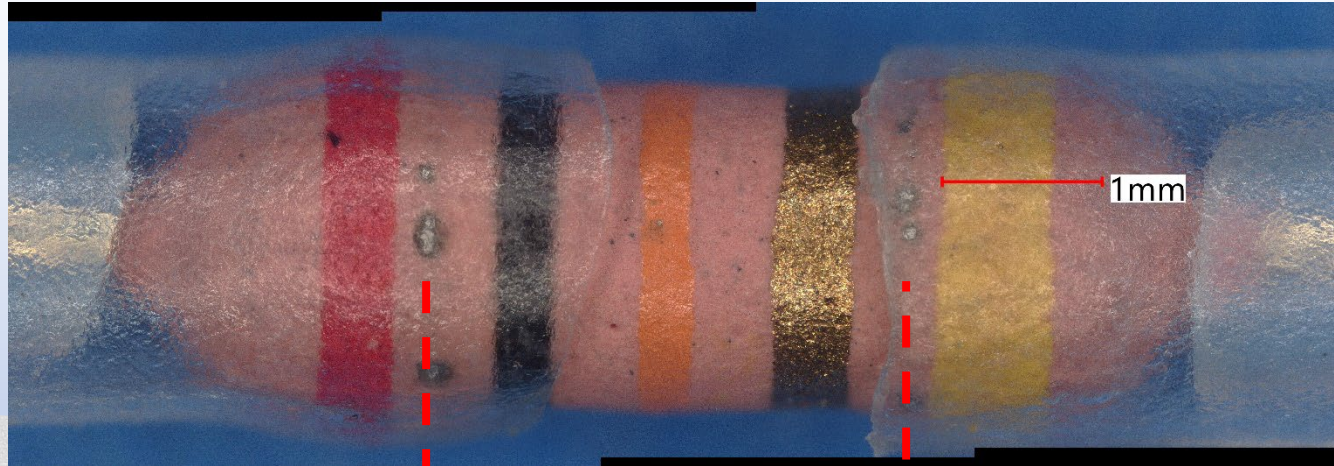
Part failed open circuit due to electrical overstress at 10kV



MFR F - End Cap Shorting



Arcing between End Caps

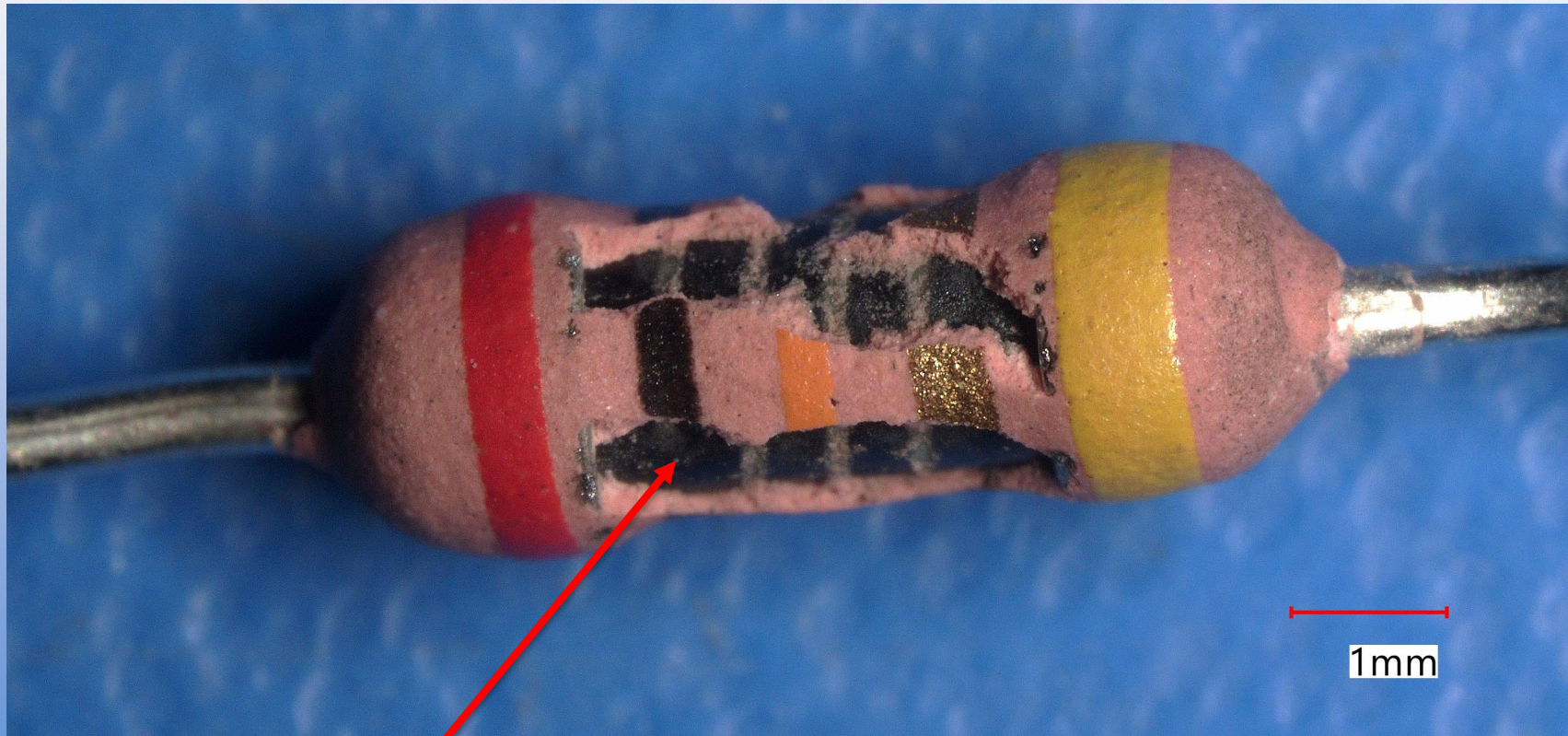


Arcing is not on resistive element, but on end caps

Fluoroinert Bath to Mitigate Arc Through Air



Severe Damage of Coating of Resistor when small part is submerged in Fluoroinert



Arcing damage is in the resistive element



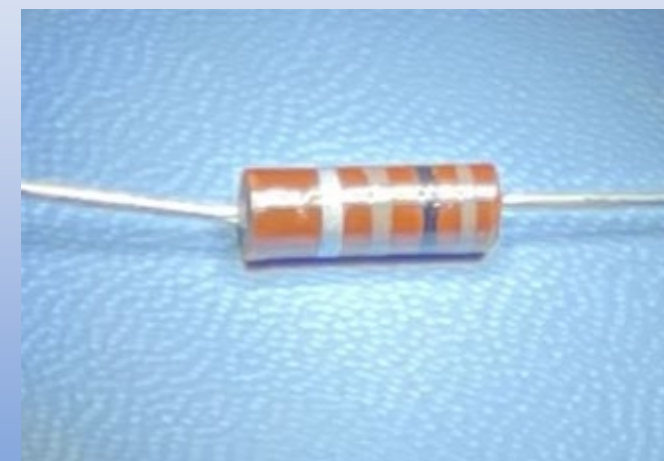
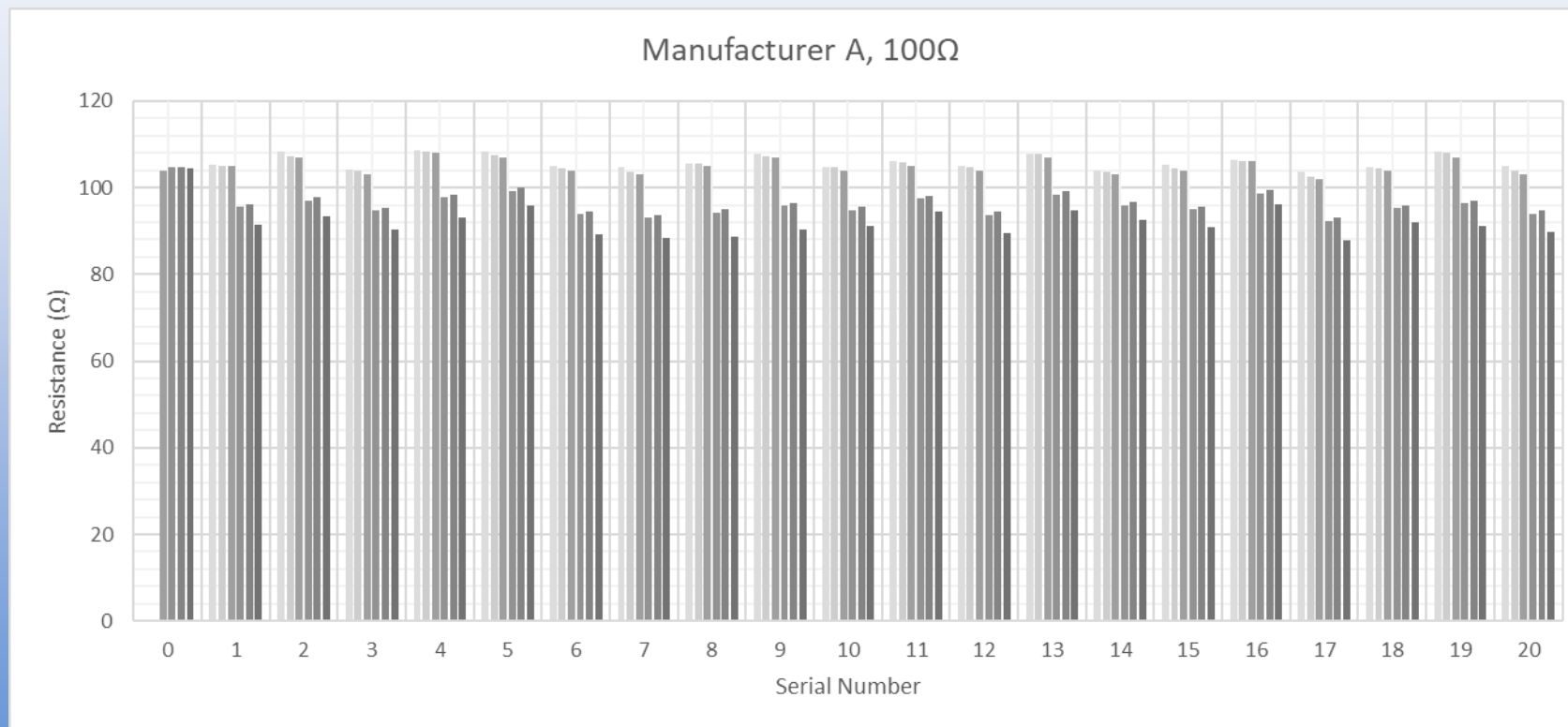
Further Work

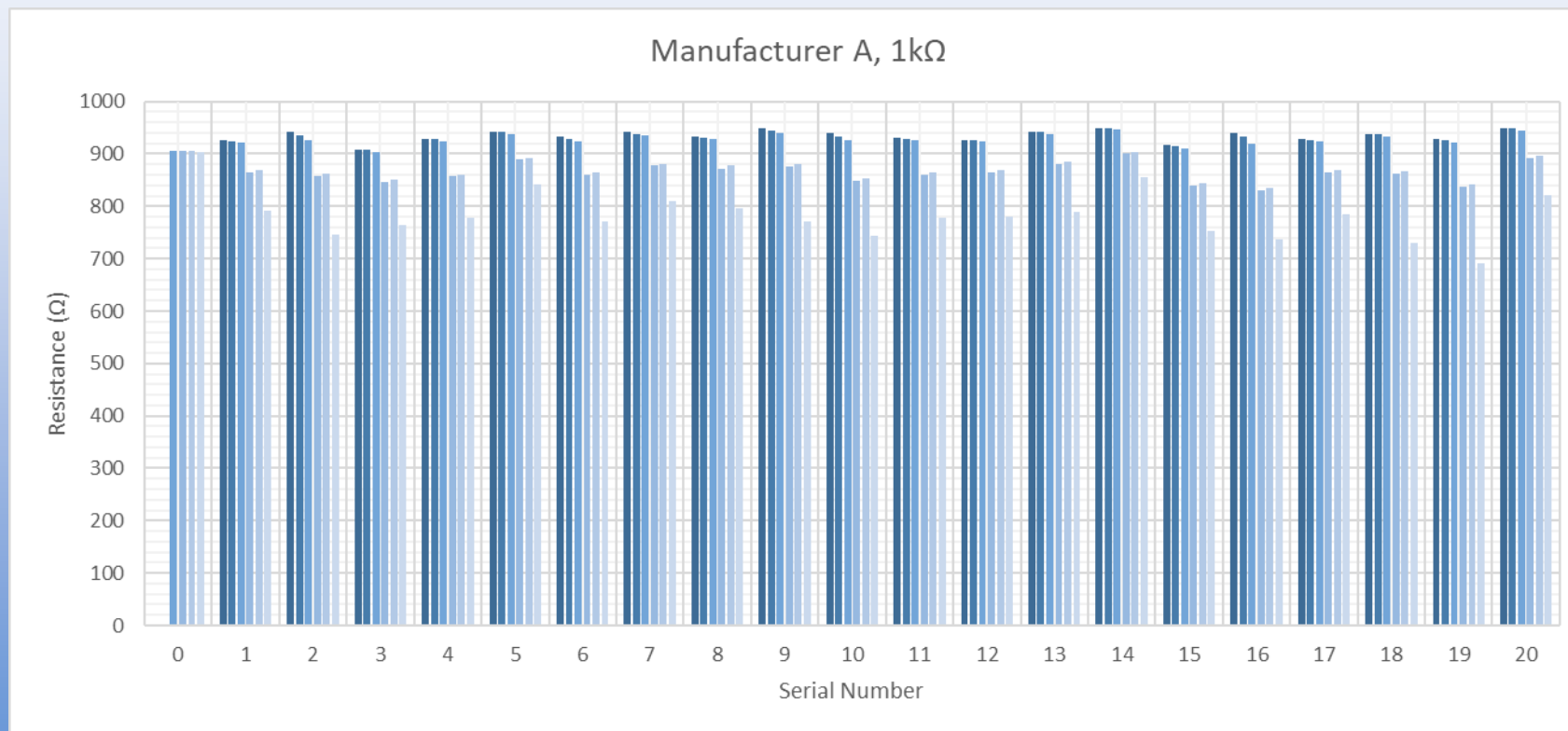
- At 10,000V, some of the smallest resistors exhibited shorting between the endcaps
 - Pulse energy was bypassing bulk material
 - Epoxy coating withstanding voltage was insufficient for 10,000V
 - Larger value capacitor will be selected and placed into the circuit, to provide more joule energy at a reduced peak voltage.
- Perform sectioning on degraded devices to document physical changes to material as a result of pulse testing.
- Assess possibility for SMD testing with minor setup changes.

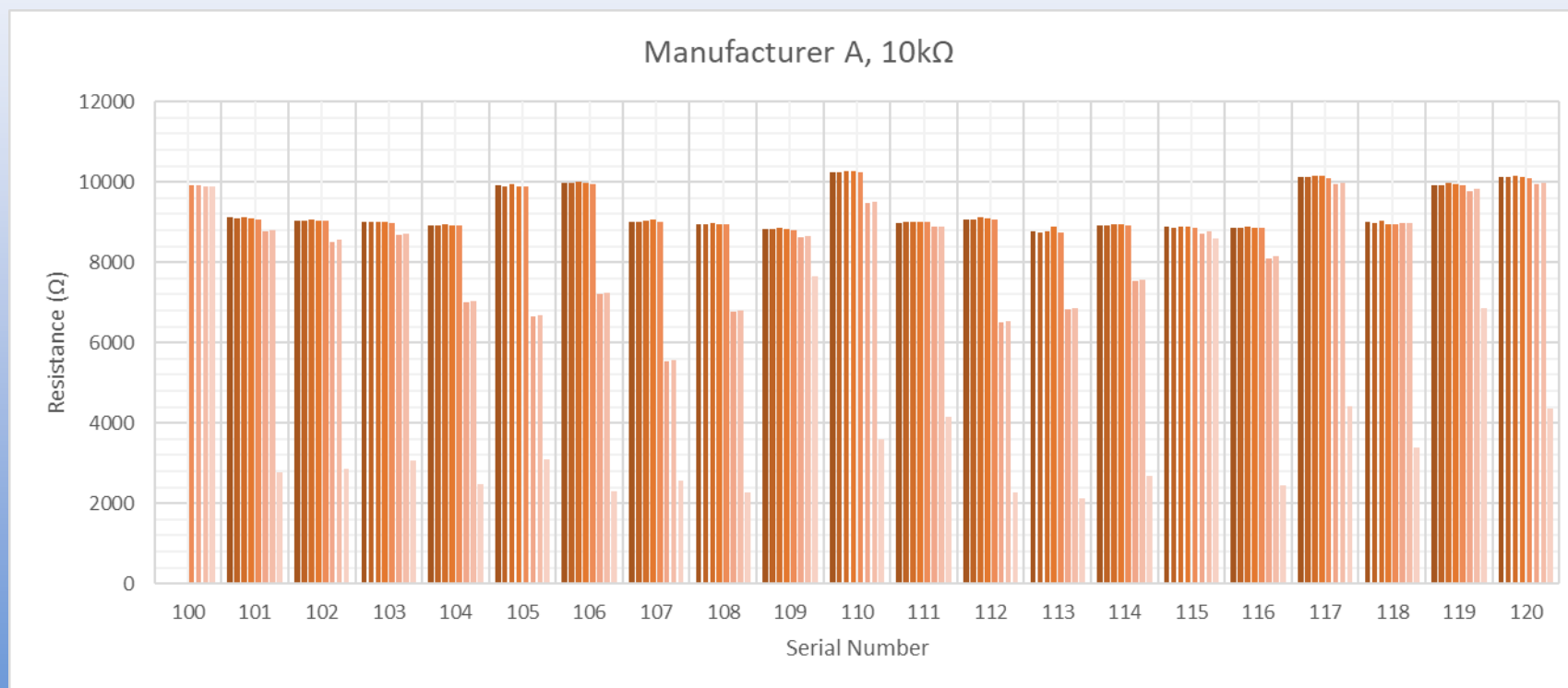


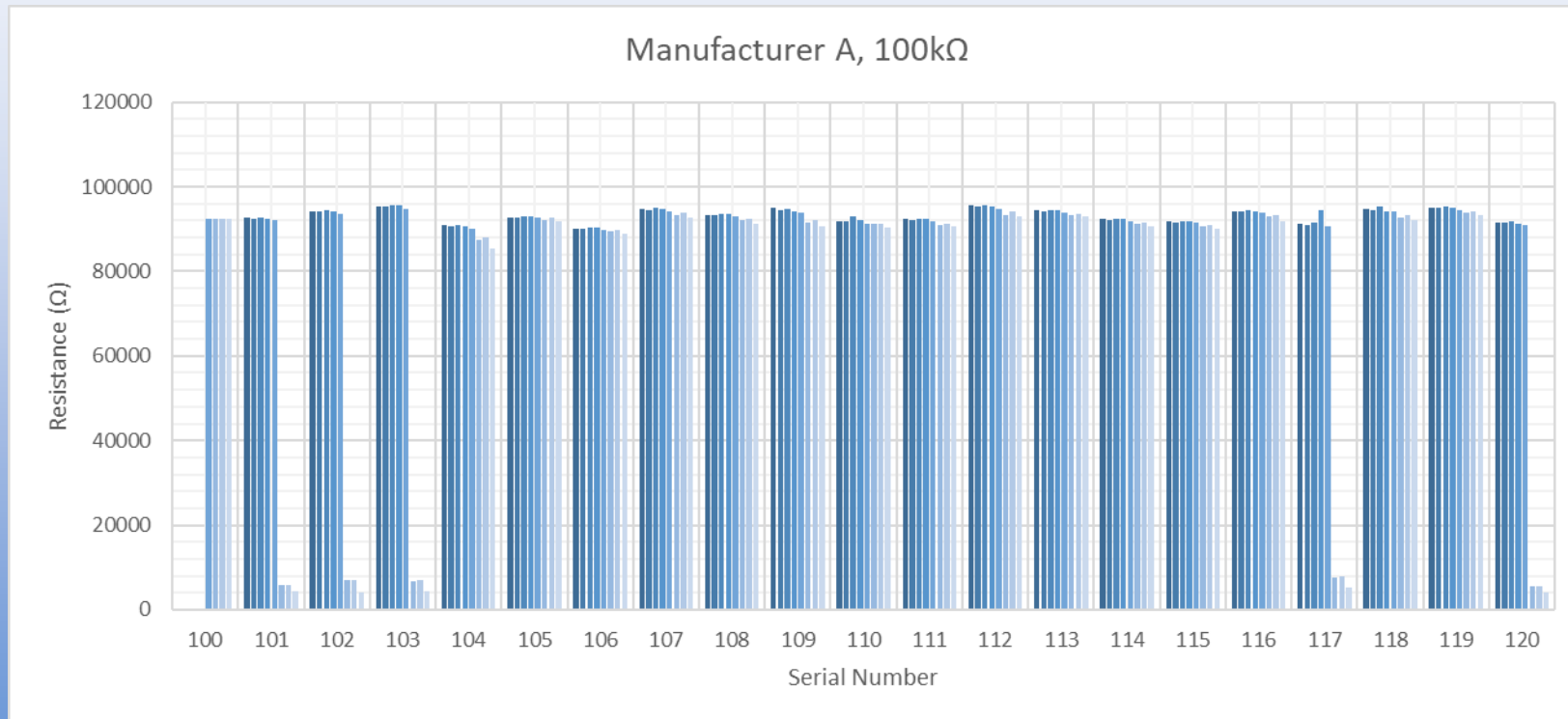
Backup Slides

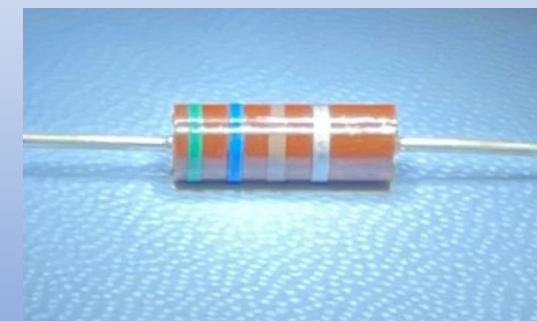
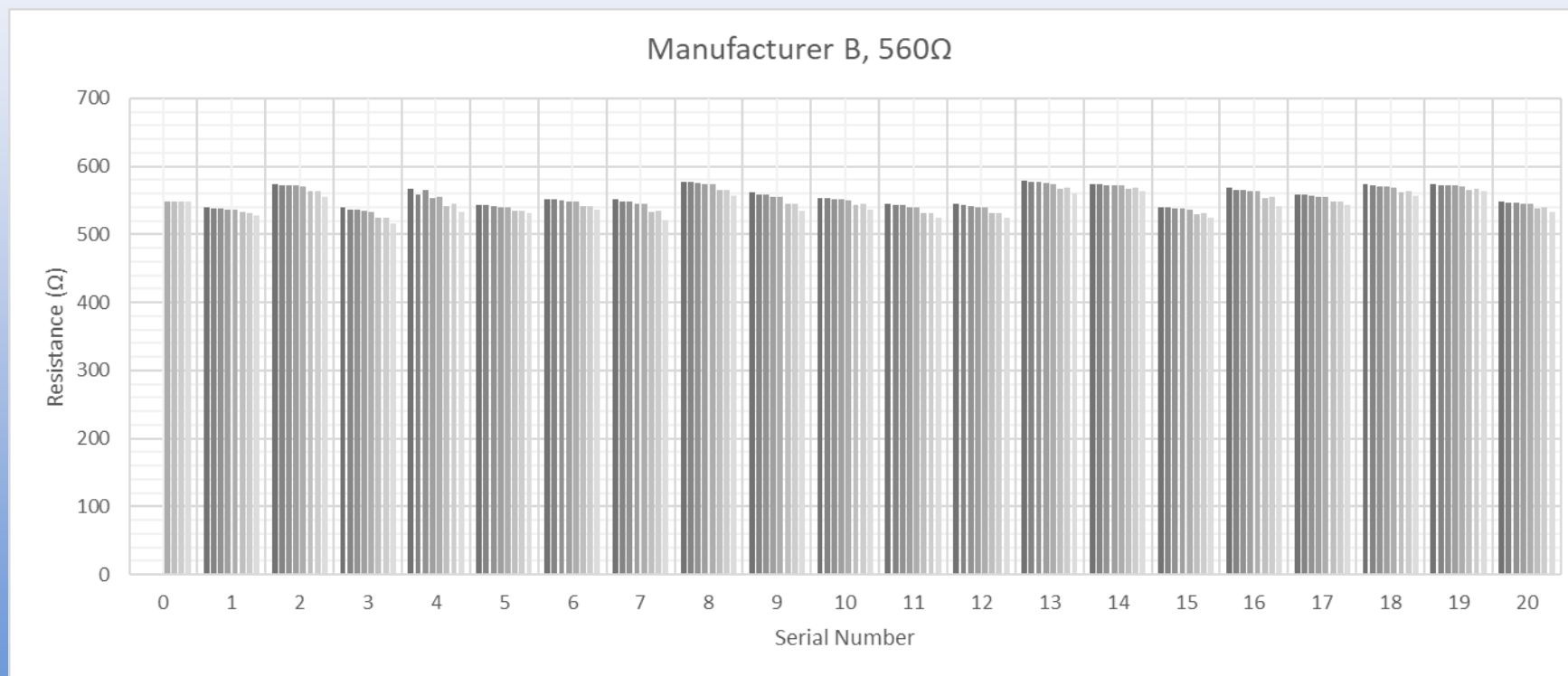
- Test Data- Remaining Sample Tests

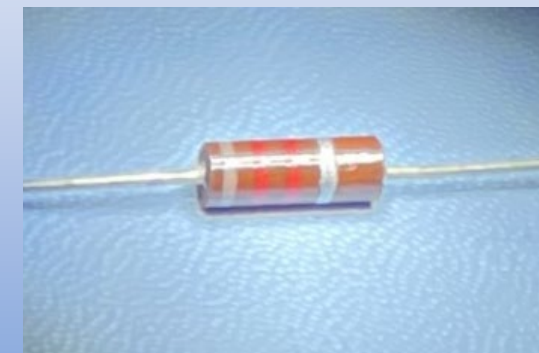
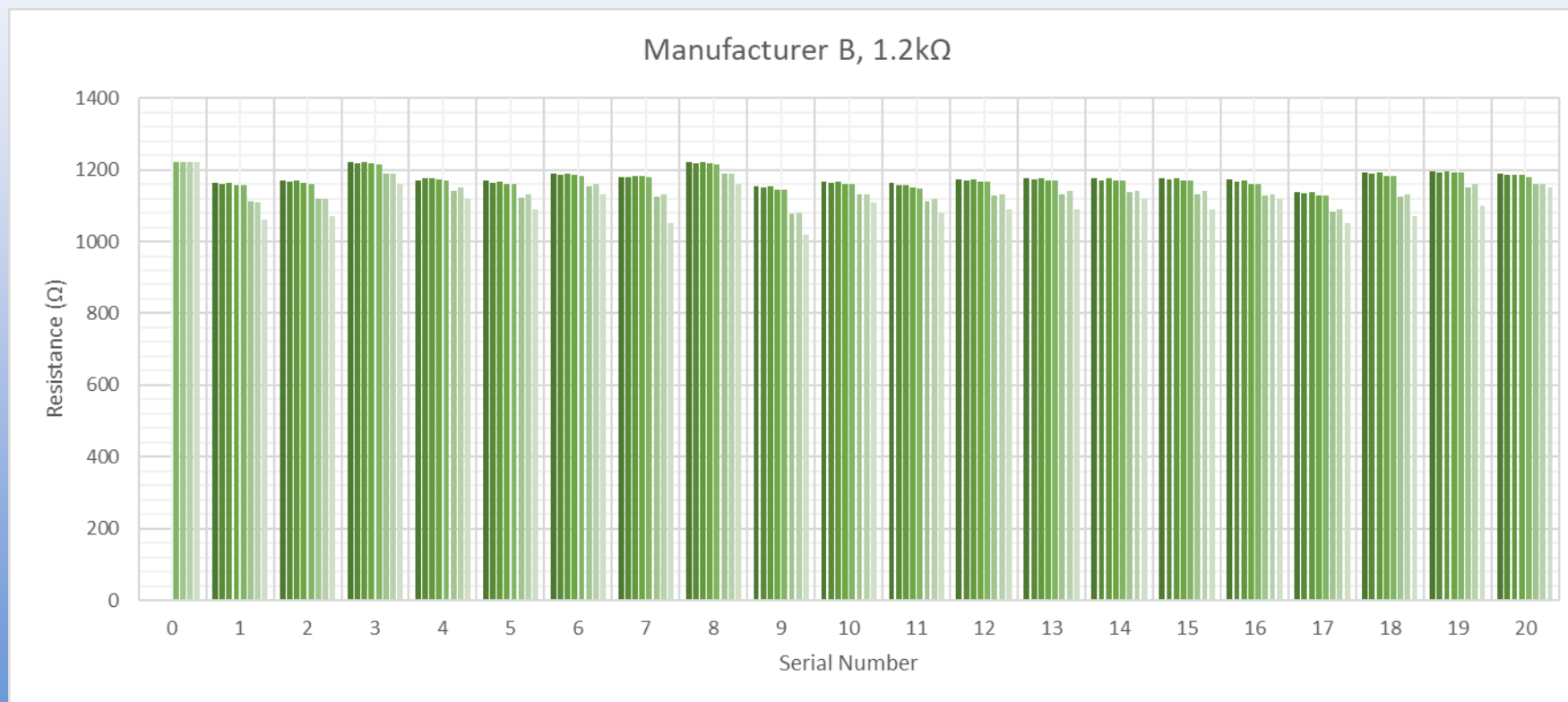


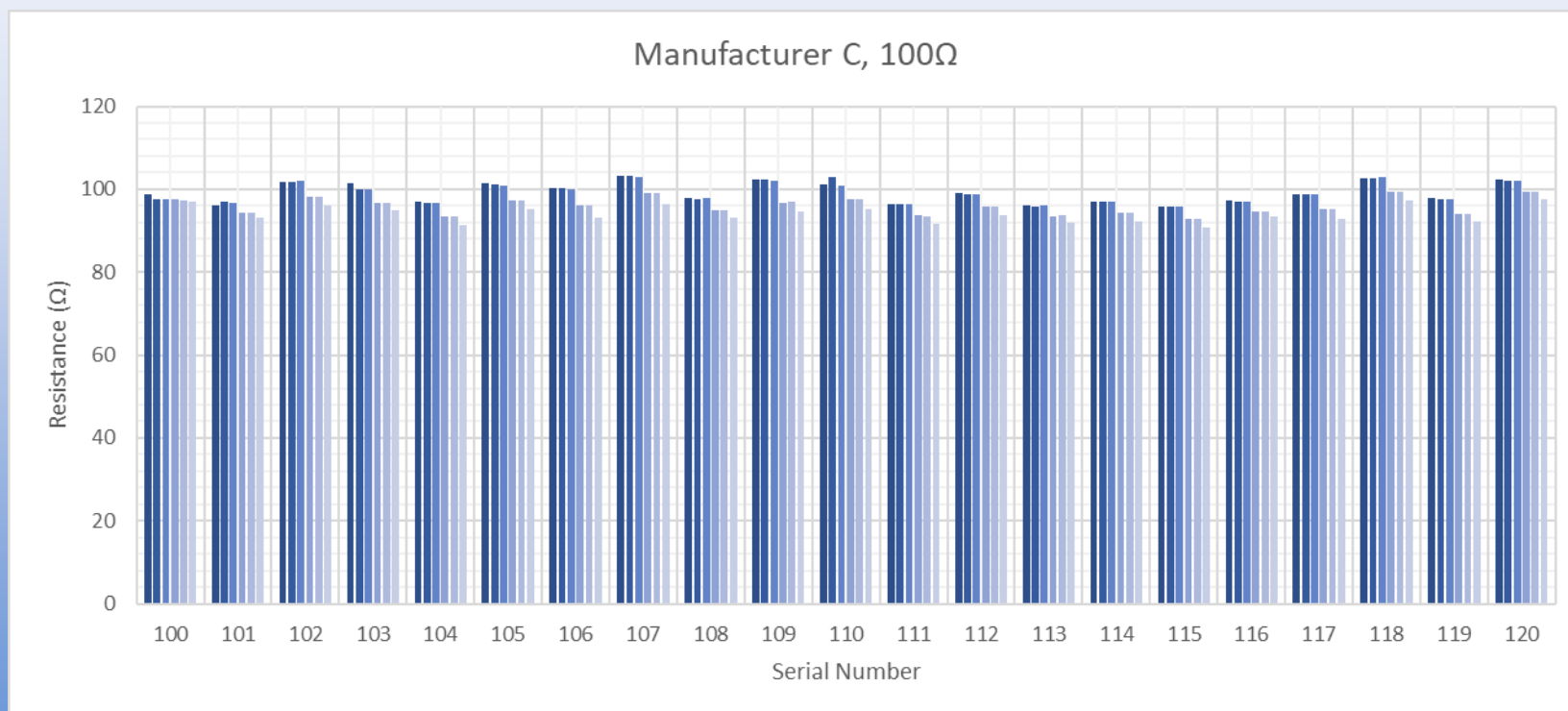




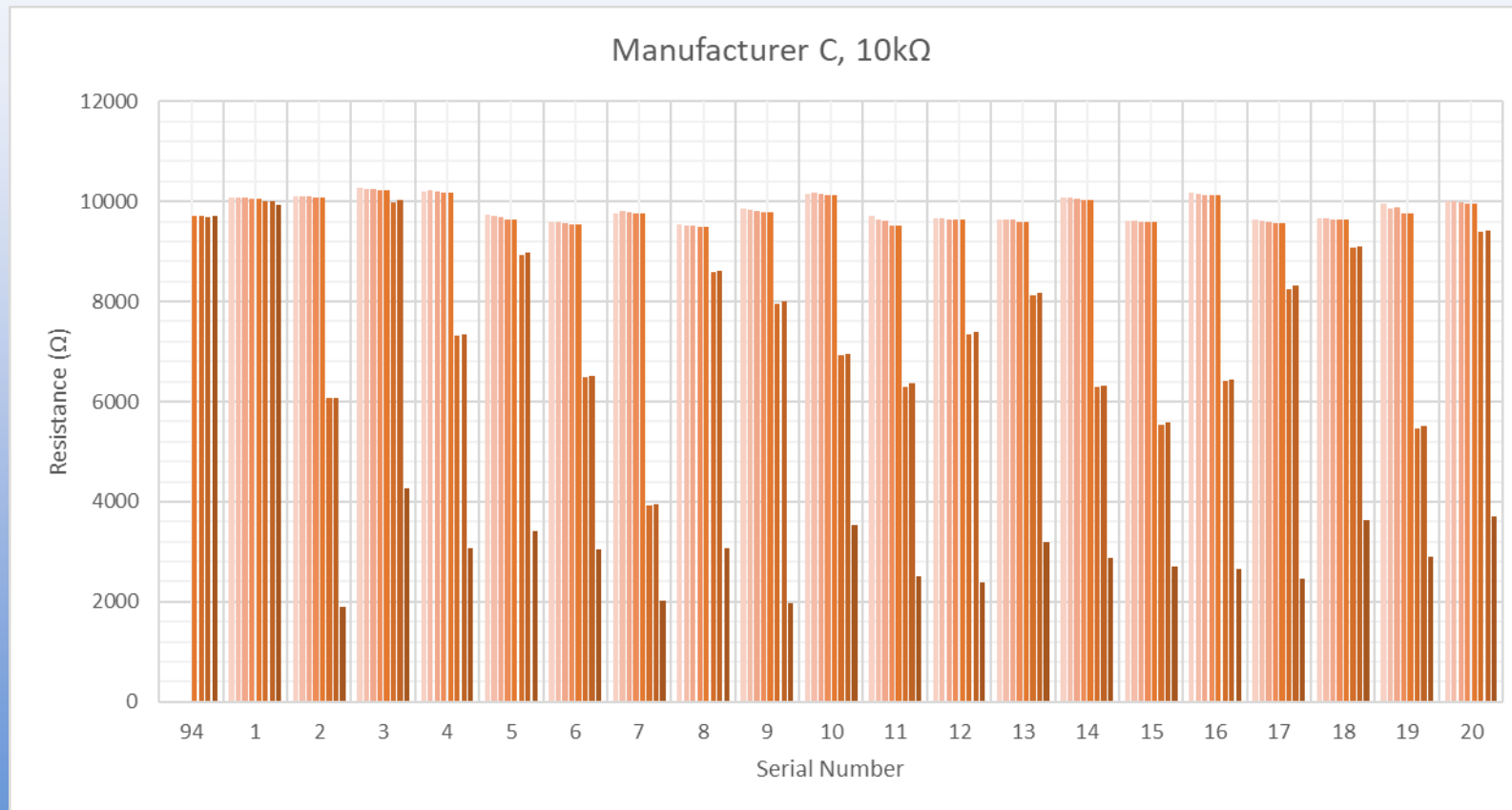


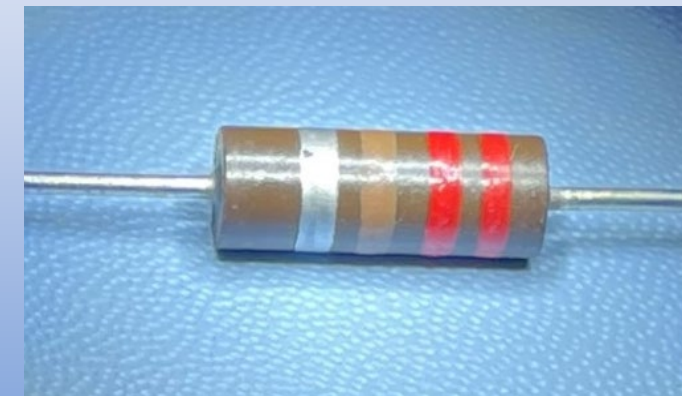
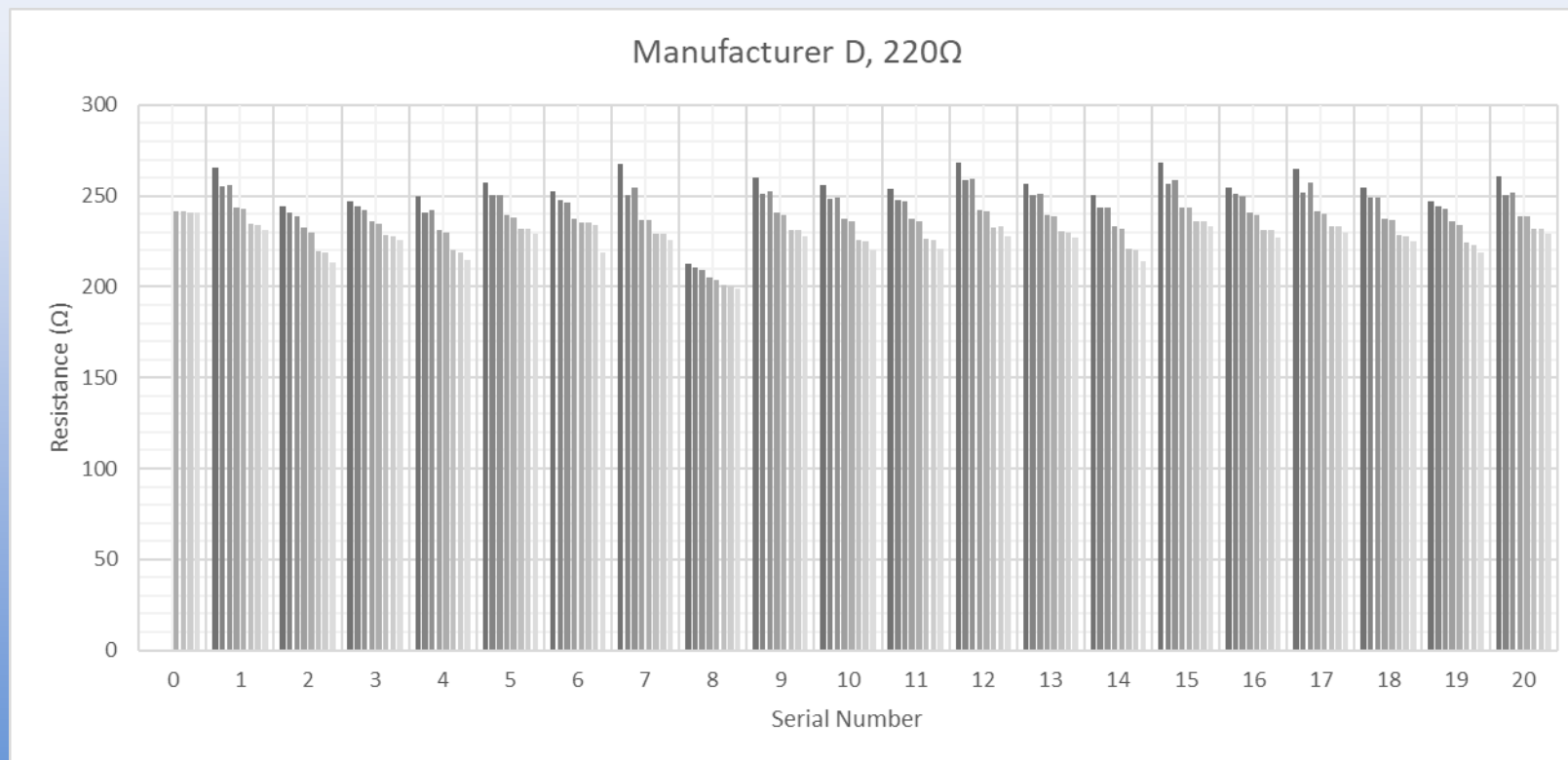












Manufacturer D, 47k Ω

